

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10673631	HWANG, YONG SUK
	<b>Examiner</b>	<b>Art Unit</b>
	Lee, Siu M	2611

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
375	326, 150, 316, 371, 354, 373, 375, 376	12/07/2006	Siu M. Lee

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
US-PGPUB	12/07/2006	Siu M. Lee
USPAT	12/07/2006	Siu M. Lee
USOCR	12/07/2006	Siu M. Lee
EPO	12/07/2006	Siu M. Lee
JPO	12/07/2006	Siu M. Lee
Derwent	12/07/2006	Siu M. Lee
IBM_TDB	12/07/2006	Siu M. Lee
Discussed the application with Chieh Fan	12/07/2006	Siu M. Lee
Discuss the application with Chieh Fan	4/18/2007	Siu M. Lee
EAST	4/18/2007	Siu M. Lee

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
375	316, 326, 327, 373, 322	4/18/2007	Siu M. Lee
455	204	4/18/2007	Siu M. Lee